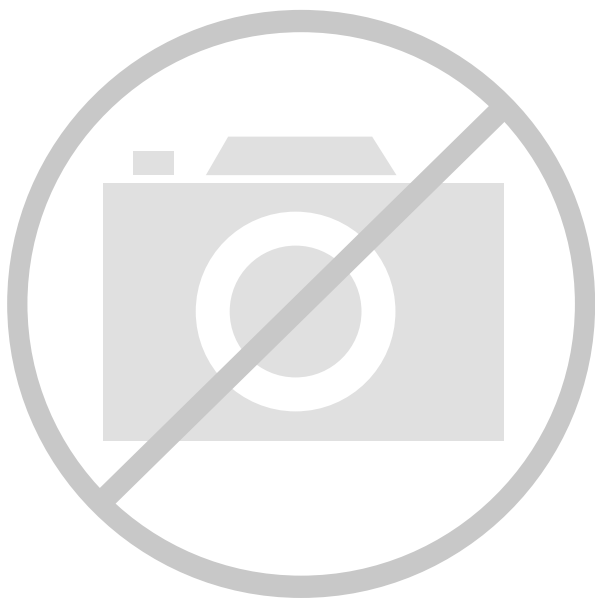




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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	110592
Number of I/O	270
Number of Gates	600000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a3pe600l-fgg484m

Table 2-28 • Summary of Maximum and Minimum DC Input Levels
Applicable to Military Conditions

DC I/O Standard	Military ¹	
	I_{IL} ²	I_{IH} ³
	μA	μA
3.3 V LVTTTL / 3.3 V LVCMOS	15	15
3.3 V LVCMOS Wide Range	15	15
2.5 V LVCMOS	15	15
1.8 V LVCMOS	15	15
1.5 V LVCMOS	15	15
1.2 V LVCMOS ⁴	15	15
1.2 V LVCMOS Wide Range ⁴	15	15
3.3 V PCI	15	15
3.3 V PCI-X	15	15
3.3 V GTL	15	15
2.5 V GTL	15	15
3.3 V GTL+	15	15
2.5 V GTL+	15	15
HSTL (I)	15	15
HSTL (II)	15	15
SSTL2 (I)	15	15
SSTL2 (II)	15	15
SSTL3 (I)	15	15
SSTL3 (II)	15	15

Notes:

1. Military temperature range: $-55^{\circ}C$ to $125^{\circ}C$.
2. I_{IL} is the input leakage current per I/O pin over recommended operation conditions where $-0.3 V < V_{IN} < V_{IL}$.
3. I_{IH} is the input leakage current per I/O pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges.
4. Applicable to Military A3PE600L and A3PE3000L devices operating at $V_{CCI} \geq V_{CC}$.

1.5 V DC Core Voltage

Table 2-88 • 1.8 V LVCMOS Low Slew

Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$, Worst-Case $V_{CCI} = 1.7\text{ V}$

Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.61	9.02	0.04	1.69	2.52	0.40	9.17	7.57	2.61	1.01	10.63	9.04	ns
	–1	0.52	7.68	0.03	1.44	2.14	0.34	7.80	6.44	2.22	0.86	9.04	7.69	ns
4 mA	Std.	0.61	7.41	0.04	1.69	2.52	0.40	7.52	6.36	3.07	2.56	8.99	7.83	ns
	–1	0.52	6.30	0.03	1.44	2.14	0.34	6.40	5.41	2.62	2.18	7.64	6.66	ns
6 mA	Std.	0.61	6.26	0.04	1.69	2.52	0.40	6.35	5.53	3.38	3.14	7.82	7.00	ns
	–1	0.52	5.33	0.03	1.44	2.14	0.34	5.40	4.71	2.88	2.67	6.65	5.95	ns
8 mA	Std.	0.61	5.88	0.04	1.69	2.52	0.40	5.96	5.37	3.45	3.30	7.42	6.83	ns
	–1	0.52	5.00	0.03	1.44	2.14	0.34	5.07	4.57	2.94	2.81	6.32	5.81	ns
12 mA	Std.	0.61	5.76	0.04	1.69	2.52	0.40	5.85	5.38	3.55	3.88	7.31	6.84	ns
	–1	0.52	4.90	0.03	1.44	2.14	0.34	4.97	4.57	3.02	3.30	6.22	5.82	ns
16 mA	Std.	0.61	5.76	0.04	1.69	2.52	0.40	5.85	5.38	3.55	3.88	7.31	6.84	ns
	–1	0.52	4.90	0.03	1.44	2.14	0.34	4.97	4.57	3.02	3.30	6.22	5.82	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-89 • 1.8 V LVCMOS High Slew

Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$, Worst-Case $V_{CCI} = 1.7\text{ V}$

Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.61	4.01	0.04	1.69	2.52	0.40	4.06	3.94	2.60	1.03	5.52	5.40	ns
	–1	0.52	3.41	0.03	1.44	2.14	0.34	3.45	3.35	2.21	0.88	4.70	4.60	ns
4 mA	Std.	0.61	3.22	0.04	1.69	2.52	0.40	3.26	2.89	3.07	2.65	4.72	4.36	ns
	–1	0.52	2.74	0.03	1.44	2.14	0.34	2.77	2.46	2.61	2.26	4.02	3.71	ns
6 mA	Std.	0.61	2.74	0.04	1.69	2.52	0.40	2.77	2.38	3.38	3.23	4.23	3.84	ns
	–1	0.52	2.33	0.03	1.44	2.14	0.34	2.36	2.02	2.88	2.75	3.60	3.27	ns
8 mA	Std.	0.61	2.65	0.04	1.69	2.52	0.40	2.68	2.28	3.45	3.40	4.14	3.75	ns
	–1	0.52	2.26	0.03	1.44	2.14	0.34	2.28	1.94	2.93	2.89	3.52	3.19	ns
12 mA	Std.	0.61	2.64	0.04	1.69	2.52	0.40	2.66	2.16	3.55	4.01	4.13	3.63	ns
	–1	0.52	2.24	0.03	1.44	2.14	0.34	2.26	1.84	3.02	3.41	3.51	3.08	ns
16 mA	Std.	0.61	2.64	0.04	1.69	2.52	0.40	2.66	2.16	3.55	4.01	4.13	3.63	ns
	–1	0.52	2.24	0.03	1.44	2.14	0.34	2.26	1.84	3.02	3.41	3.51	3.08	ns

Notes:

- Software default selection highlighted in gray.
- For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-90 • 1.8 V LVC MOS Low Slew

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$, Worst-Case $V_{CCI} = 1.7\text{ V}$
Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.63	9.50	0.05	1.44	0.45	9.68	8.31	3.06	1.76	12.14	10.77	ns
	–1	0.54	8.08	0.04	1.23	0.39	8.23	7.07	2.60	1.50	10.32	9.16	ns
4 mA	Std.	0.63	7.80	0.05	1.44	0.45	7.95	7.06	3.55	3.01	10.41	9.52	ns
	–1	0.54	6.64	0.04	1.23	0.39	6.76	6.00	3.02	2.56	8.85	8.10	ns
6 mA	Std.	0.63	6.70	0.05	1.44	0.45	6.82	6.25	3.89	3.60	9.28	8.70	ns
	–1	0.54	5.70	0.04	1.23	0.39	5.80	5.31	3.31	3.06	7.90	7.40	ns
8 mA	Std.	0.63	6.31	0.05	1.44	0.45	6.43	6.07	3.97	3.75	8.89	8.53	ns
	–1	0.54	5.37	0.04	1.23	0.39	5.47	5.17	3.37	3.19	7.56	7.26	ns
12 mA	Std.	0.63	6.18	0.05	1.44	0.45	6.30	6.15	4.08	4.34	8.76	8.61	ns
	–1	0.54	5.26	0.04	1.23	0.39	5.36	5.23	3.47	3.70	7.45	7.32	ns
16 mA	Std.	0.63	6.18	0.05	1.44	0.45	6.30	6.15	4.08	4.34	8.76	8.61	ns
	–1	0.54	5.26	0.04	1.23	0.39	5.36	5.23	3.47	3.70	7.45	7.32	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Table 2-91 • 1.8 V LVC MOS High Slew

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$, Worst-Case $V_{CCI} = 1.7\text{ V}$
Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.63	4.40	0.05	1.34	0.45	4.48	4.30	3.05	1.82	6.94	6.76	ns
	–1	0.54	3.74	0.04	1.14	0.39	3.81	3.66	2.59	1.55	5.90	5.75	ns
4 mA	Std.	0.63	3.44	0.05	1.34	0.45	3.50	3.23	3.54	3.12	5.96	5.69	ns
	–1	0.54	2.92	0.04	1.14	0.39	2.98	2.75	3.01	2.66	5.07	4.84	ns
6 mA	Std.	0.63	3.02	0.05	1.34	0.45	3.07	2.70	3.88	3.72	5.53	5.16	ns
	–1	0.54	2.57	0.04	1.14	0.39	2.61	2.30	3.30	3.16	4.71	4.39	ns
8 mA	Std.	0.63	2.94	0.05	1.34	0.45	2.99	2.60	3.96	3.87	5.45	5.06	ns
	–1	0.54	2.50	0.04	1.14	0.39	2.54	2.21	3.37	3.30	4.64	4.31	ns
12 mA	Std.	0.63	2.93	0.05	1.34	0.45	2.98	2.49	4.07	4.49	5.44	4.95	ns
	–1	0.54	2.49	0.04	1.14	0.39	2.54	2.12	3.46	3.82	4.63	4.21	ns
16 mA	Std.	0.63	2.93	0.05	1.34	0.45	2.98	2.49	4.07	4.49	5.44	4.95	ns
	–1	0.54	2.49	0.04	1.14	0.39	2.54	2.12	3.46	3.82	4.63	4.21	ns

Notes:

- Software default selection highlighted in gray.
- For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Timing Characteristics

1.2 V DC Core Voltage

Table 2-98 • 1.5 V LVCMOS Low Slew

Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.80	9.53	0.05	2.19	3.06	0.52	9.69	7.88	3.38	2.67	11.90	10.09	ns
	–1	0.68	8.10	0.05	1.86	2.61	0.44	8.25	6.71	2.87	2.27	10.12	8.58	ns
4 mA	Std.	0.80	8.14	0.05	2.19	3.06	0.52	8.28	6.89	3.74	3.34	10.49	9.09	ns
	–1	0.68	6.93	0.05	1.86	2.61	0.44	7.05	5.86	3.18	2.84	8.92	7.74	ns
6 mA	Std.	0.80	7.64	0.05	2.19	3.06	0.52	7.78	6.70	3.82	3.52	9.98	8.91	ns
	–1	0.68	6.50	0.05	1.86	2.61	0.44	6.61	5.70	3.25	2.99	8.49	7.58	ns
8 mA	Std.	0.80	7.55	0.05	2.19	3.06	0.52	7.68	6.71	3.41	4.19	9.88	8.91	ns
	–1	0.68	6.42	0.05	1.86	2.61	0.44	6.53	5.71	2.90	3.56	8.41	7.58	ns
12 mA	Std.	0.80	7.55	0.05	2.19	3.06	0.52	7.68	6.71	3.41	4.19	9.88	8.91	ns
	–1	0.68	6.42	0.05	1.86	2.61	0.44	6.53	5.71	2.90	3.56	8.41	7.58	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-99 • 1.5 V LVCMOS High Slew

Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 1.4 V
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	Std.	0.80	3.91	0.05	2.19	3.06	0.52	3.98	3.54	3.37	2.78	6.18	5.75	ns
	–1	0.68	3.33	0.05	1.86	2.61	0.44	3.38	3.01	2.86	2.36	5.26	4.89	ns
4 mA	Std.	0.80	3.34	0.05	2.19	3.06	0.52	3.39	2.90	3.73	3.45	5.60	5.11	ns
	–1	0.68	2.84	0.05	1.86	2.61	0.44	2.88	2.47	3.17	2.93	4.76	4.35	ns
6 mA	Std.	0.80	3.23	0.05	2.19	3.06	0.52	3.28	2.78	3.81	3.64	5.48	4.99	ns
	–1	0.68	2.74	0.05	1.86	2.61	0.44	2.79	2.37	3.24	3.09	4.66	4.24	ns
8 mA	Std.	0.80	3.19	0.05	2.19	3.06	0.52	3.24	2.63	3.93	4.33	5.45	4.84	ns
	–1	0.68	2.71	0.05	1.86	2.61	0.44	2.76	2.24	3.34	3.69	4.63	4.12	ns
12 mA	Std.	0.80	3.19	0.05	2.19	3.06	0.52	3.24	2.63	3.93	4.33	5.45	4.84	ns
	–1	0.68	2.71	0.05	1.86	2.61	0.44	2.76	2.24	3.34	3.69	4.63	4.12	ns

Notes:

- Software default selection highlighted in gray.
- For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Timing Characteristics

Table 2-112 • 1.2 V LVCMOS Wide Range Low Slew

Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.14\text{ V}$, Worst-Case $V_{CCI} = 1.4\text{ V}$
Applicable to Pro I/O Banks for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
100 μA	Std.	0.80	12.61	0.05	2.65	3.75	0.52	12.10	9.50	5.11	4.66	14.31	11.71	ns
	–1	0.68	10.72	0.05	2.25	3.19	0.44	10.30	8.08	4.35	3.97	12.17	9.96	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-113 • 1.2 V LVCMOS Wide Range High Slew

Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.14\text{ V}$, Worst-Case $V_{CCI} = 1.4\text{ V}$
Applicable to Pro I/O Banks for A3PE600L and A3PE3000L Only

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Unit s
100 μA	Std.	0.80	5.16	0.05	2.65	3.75	0.52	4.98	4.39	5.10	4.81	7.19	6.60	ns
	–1	0.68	4.39	0.05	2.25	3.19	0.44	4.24	3.74	4.34	4.09	6.11	5.61	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-155 • SSTL3 Class I

Military-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.425\text{ V}$,
Worst-Case $V_{CCI} = 3.0\text{ V}$, $V_{REF} = 1.5\text{ V}$
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
Std.	0.61	2.15	0.04	1.77	0.40	2.17	1.70	—	—	2.17	1.70	ns
–1	0.52	1.83	0.03	1.51	0.34	1.84	1.45	—	—	1.84	1.45	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

SSTL3 Class II

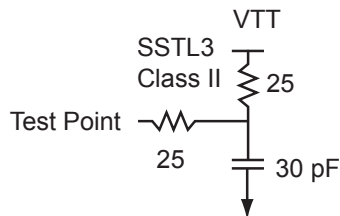
Stub-Speed Terminated Logic for 3.3 V memory bus standard (JESD8-8). Military ProASIC3E devices support Class II. This provides a differential amplifier input buffer and a push-pull output buffer.

Table 2-156 • Minimum and Maximum DC Input and Output Levels

SSTL3 Class II	VIL		VIH		VOL	VOH	IOL	IOH	IOL	IOSH	IIL	IIH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
21 mA	–0.3	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	0.5	$V_{CCI} - 0.9$	21	21	103	109	15	15

Notes:

1. Currents are measured at 100°C junction temperature and maximum voltage.
2. Currents are measured at 125°C junction temperature.


Figure 2-24 • AC Loading
Table 2-157 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	V_{REF} (typ.) (V)	V_{TT} (typ.) (V)	C_{LOAD} (pF)
$V_{REF} - 0.2$	$V_{REF} + 0.2$	1.5	1.5	1.485	30

Note: *Measuring point = V_{trip} . See Table 2-29 on page 2-25 for a complete table of trip points.

Timing Characteristics

Table 2-158 • SSTL3 Class II

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case $V_{CC} = 1.14\text{ V}$,
Worst-Case $V_{CCI} = 3.0\text{ V}$, $V_{REF} = 1.5\text{ V}$
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
Std.	0.80	2.05	0.05	2.00	0.52	2.08	1.65	—	—	2.08	1.65	ns
–1	0.68	1.75	0.05	1.71	0.44	1.77	1.41	—	—	1.77	1.41	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Table 2-160 • Minimum and Maximum DC Input and Output Levels

DC Parameter	Description	Min.	Typ.	Max.	Units
VCCI	Supply Voltage	2.375	2.5	2.625	V
VOL	Output Low Voltage	0.9	1.075	1.25	V
VOH	Output High Voltage	1.25	1.425	1.6	V
IOL ¹	Output Lower Current	0.65	0.91	1.16	mA
IOH ¹	Output High Current	0.65	0.91	1.16	mA
VI	Input Voltage	0	–	2.925	V
IIH ^{2,3}	Input High Leakage Current	–	–	10	μA
IIL ^{2,4}	Input Low Leakage Current	–	–	10	μA
VODIFF	Differential Output Voltage	250	350	450	mV
VOCM	Output Common Mode Voltage	1.125	1.25	1.375	V
VICM	Input Common Mode Voltage	0.05	1.25	2.35	V
VIDIFF	Input Differential Voltage	100	350	–	mV

Notes:

1. IOL/IOH is defined by VODIFF/(Resistor Network).
2. Currents are measured at 125°C junction temperature.
3. IIH is the input leakage current per IO pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges.
4. IIL is the input leakage current per I/O pin over recommended operation conditions where $-0.3\text{ V} < V_{IN} < V_{IL}$.

Table 2-161 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)
1.075	1.325	Cross point

Note: *Measuring point = V_{trip} . See Table 2-29 on page 2-25 for a complete table of trip points.

LVPECL

Low-Voltage Positive Emitter-Coupled Logic (LVPECL) is another differential I/O standard. It requires that one data bit be carried through two signal lines. Like LVDS, two pins are needed. It also requires external resistor termination.

The full implementation of the LVDS transmitter and receiver is shown in an example in [Figure 2-27](#). The building blocks of the LVPECL transmitter-receiver are one transmitter macro, one receiver macro, three board resistors at the transmitter end, and one resistor at the receiver end. The values for the three driver resistors are different from those used in the LVDS implementation because the output standard specifications are different.

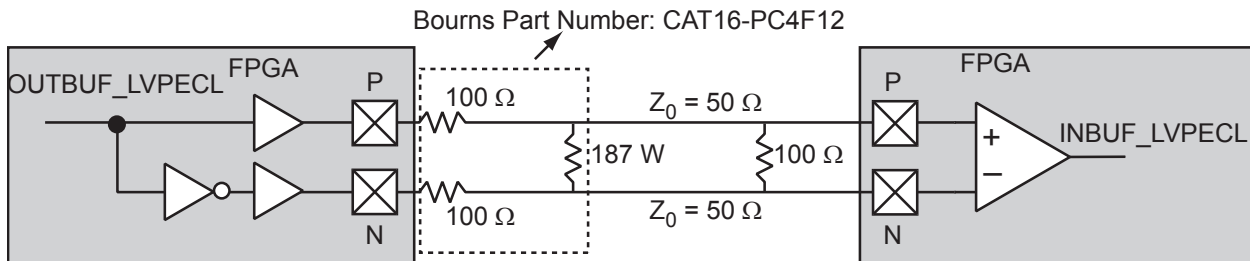


Figure 2-27 • LVPECL Circuit Diagram and Board-Level Implementation

Table 2-165 • Minimum and Maximum DC Input and Output Levels

DC Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
VCCI	Supply Voltage	3.0		3.3		3.6		V
VOL	Output Low Voltage	0.96	1.27	1.06	1.43	1.30	1.57	V
VOH	Output High Voltage	1.8	2.11	1.92	2.28	2.13	2.41	V
VIL, VIH	Input Low, Input High Voltages	0	3.3	0	3.6	0	3.9	V
VODIFF	Differential Output Voltage	0.625	0.97	0.625	0.97	0.625	0.97	V
VOCM	Output Common-Mode Voltage	1.762	1.98	1.762	1.98	1.762	1.98	V
VICM	Input Common-Mode Voltage	1.01	2.57	1.01	2.57	1.01	2.57	V
VIDIFF	Input Differential Voltage	300		300		300		mV

Table 2-166 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)
1.64	1.94	Cross point

Note: *Measuring point = V_{trip} . See [Table 2-29](#) on page 2-25 for a complete table of trip points.

Table 2-180 • Output Enable Register Propagation Delays
Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$ for A3P250 and A3P1000

Parameter	Description	–1	Std.	Units
t_{OECLKQ}	Clock-to-Q of the Output Enable Register	0.54	0.63	ns
t_{OESUD}	Data Setup Time for the Output Enable Register	0.38	0.44	ns
t_{OEHD}	Data Hold Time for the Output Enable Register	0.00	0.00	ns
t_{OESUE}	Enable Setup Time for the Output Enable Register	0.52	0.62	ns
t_{OEHE}	Enable Hold Time for the Output Enable Register	0.00	0.00	ns
$t_{OECLR2Q}$	Asynchronous Clear-to-Q of the Output Enable Register	0.80	0.94	ns
$t_{OEPRE2Q}$	Asynchronous Preset-to-Q of the Output Enable Register	0.80	0.94	ns
$t_{OEREMCLR}$	Asynchronous Clear Removal Time for the Output Enable Register	0.00	0.00	ns
$t_{OERECCLR}$	Asynchronous Clear Recovery Time for the Output Enable Register	0.27	0.31	ns
$t_{OEREMPRE}$	Asynchronous Preset Removal Time for the Output Enable Register	0.00	0.00	ns
$t_{OERECPRE}$	Asynchronous Preset Recovery Time for the Output Enable Register	0.27	0.31	ns
$t_{OEWCCLR}$	Asynchronous Clear Minimum Pulse Width for the Output Enable Register	0.25	0.30	ns
t_{OEWPPE}	Asynchronous Preset Minimum Pulse Width for the Output Enable Register	0.25	0.30	ns
$t_{OECKMPWH}$	Clock Minimum Pulse Width HIGH for the Output Enable Register	0.41	0.48	ns
$t_{OECKMPWL}$	Clock Minimum Pulse Width LOW for the Output Enable Register	0.37	0.43	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

DDR Module Specifications

Input DDR Module

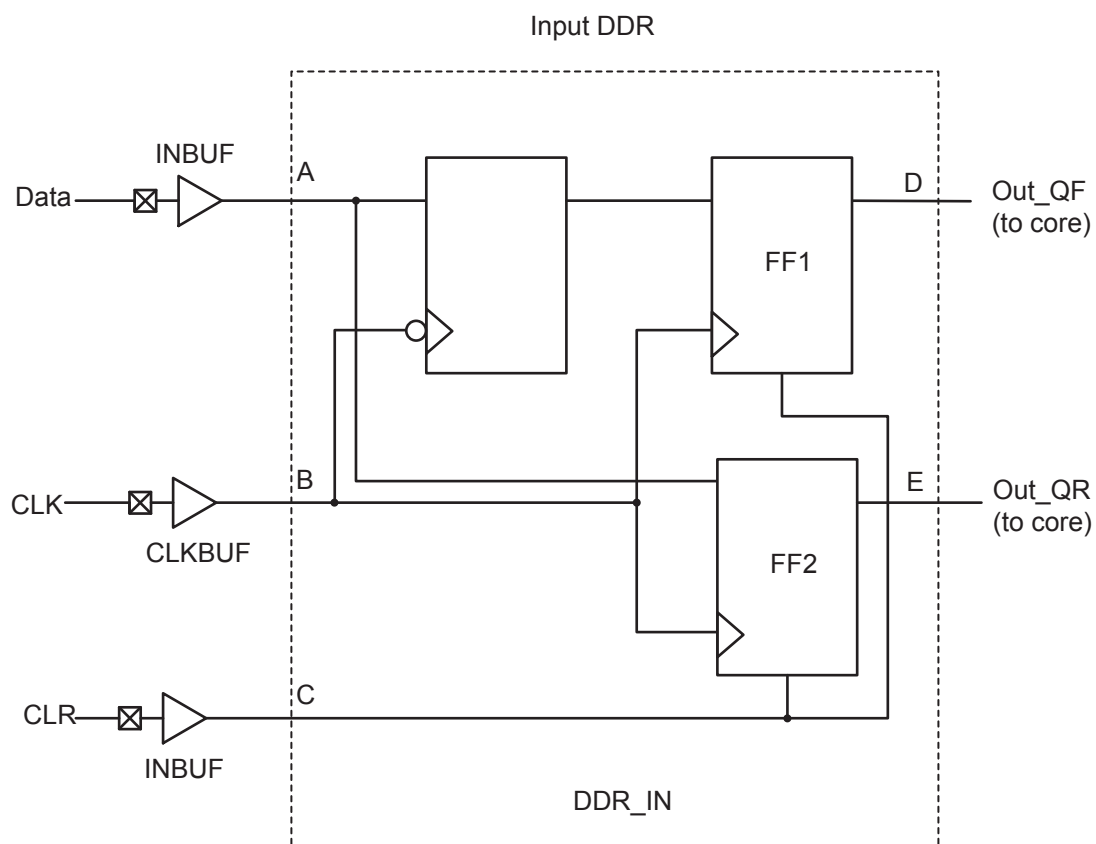


Figure 2-33 • Input DDR Timing Model

Table 2-181 • Parameter Definitions

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
$t_{DDRICKQ1}$	Clock-to-Out Out_QR	B, D
$t_{DDRICKQ2}$	Clock-to-Out Out_QF	B, E
$t_{DDRISUD}$	Data Setup Time of DDR input	A, B
t_{DDRIRD}	Data Hold Time of DDR input	A, B
$t_{DDRICLR2Q1}$	Clear-to-Out Out_QR	C, D
$t_{DDRICLR2Q2}$	Clear-to-Out Out_QF	C, E
$t_{DDRIRECLR}$	Clear Removal	C, B
$t_{DDRIRECLR}$	Clear Recovery	C, B

Timing Characteristics

Table 2-189 • Combinatorial Cell Propagation Delays

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case $V_{CC} = 1.14\text{ V}$ for A3PE600L and A3PE3000L

Combinatorial Cell	Equation	Parameter	–1	Std.	Units
INV	$Y = !A$	t_{PD}	0.56	0.65	ns
AND2	$Y = A \cdot B$	t_{PD}	0.65	0.77	ns
NAND2	$Y = !(A \cdot B)$	t_{PD}	0.65	0.77	ns
OR2	$Y = A + B$	t_{PD}	0.67	0.79	ns
NOR2	$Y = !(A + B)$	t_{PD}	0.67	0.79	ns
XOR2	$Y = A \oplus B$	t_{PD}	1.02	1.20	ns
MAJ3	$Y = \text{MAJ}(A, B, C)$	t_{PD}	0.97	1.14	ns
XOR3	$Y = A \oplus B \oplus C$	t_{PD}	1.21	1.42	ns
MUX2	$Y = A !S + B S$	t_{PD}	0.70	0.82	ns
AND3	$Y = A \cdot B \cdot C$	t_{PD}	0.78	0.91	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-190 • Combinatorial Cell Propagation Delays

Military-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.425\text{ V}$ for any A3PE600L/A3PE3000L

Combinatorial Cell	Equation	Parameter	–1	Std.	Units
INV	$Y = !A$	t_{PD}	0.43	0.50	ns
AND2	$Y = A \cdot B$	t_{PD}	0.50	0.59	ns
NAND2	$Y = !(A \cdot B)$	t_{PD}	0.50	0.59	ns
OR2	$Y = A + B$	t_{PD}	0.51	0.61	ns
NOR2	$Y = !(A + B)$	t_{PD}	0.51	0.61	ns
XOR2	$Y = A \oplus B$	t_{PD}	0.78	0.92	ns
MAJ3	$Y = \text{MAJ}(A, B, C)$	t_{PD}	0.74	0.87	ns
XOR3	$Y = A \oplus B \oplus C$	t_{PD}	0.93	1.09	ns
MUX2	$Y = A !S + B S$	t_{PD}	0.54	0.63	ns
AND3	$Y = A \cdot B \cdot C$	t_{PD}	0.59	0.70	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Global Tree Timing Characteristics

Global clock delays include the central rib delay, the spine delay, and the row delay. Delays do not include I/O input buffer clock delays, as these are I/O standard-dependent, and the clock may be driven and conditioned internally by the CCC module. For more details on clock conditioning capabilities, refer to the "Clock Conditioning Circuits" section on page 2-123. Table 2-195 to Table 2-198 on page 2-121 present minimum and maximum global clock delays within each device. Minimum and maximum delays are measured with minimum and maximum loading.

Timing Characteristics

1.2 V DC Core Voltage

Table 2-195 • A3PE600L Global Resource
Military-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	-1		Std.		Units
		Min. ¹	Max. ²	Min. ¹	Max. ²	
t_{RCKL}	Input LOW Delay for Global Clock	0.95	1.23	1.12	1.44	ns
t_{RCKH}	Input HIGH Delay for Global Clock	0.94	1.26	1.10	1.48	ns
$t_{RCKMPWH}$	Minimum Pulse Width HIGH for Global Clock					ns
$t_{RCKMPWL}$	Minimum Pulse Width LOW for Global Clock					ns
t_{RCKSW}	Maximum Skew for Global Clock		0.32		0.38	ns
F_{RMAX}	Maximum Frequency for Global Clock					MHz

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Table 2-196 • A3PE3000L Global Resource
Military-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.14\text{ V}$

Parameter	Description	-1		Std.		Units
		Min. ¹	Max. ²	Min. ¹	Max. ²	
t_{RCKL}	Input LOW Delay for Global Clock	1.81	2.09	2.13	2.42	ns
t_{RCKH}	Input HIGH Delay for Global Clock	1.80	2.13	2.12	2.45	ns
$t_{RCKMPWH}$	Minimum Pulse Width HIGH for Global Clock					ns
$t_{RCKMPWL}$	Minimum Pulse Width LOW for Global Clock					ns
t_{RCKSW}	Maximum Skew for Global Clock		0.32		0.38	ns
F_{RMAX}	Maximum Frequency for Global Clock					MHz

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Clock Conditioning Circuits

CCC Electrical Specifications

Timing Characteristics

Table 2-201 • Military ProASIC3/EL CCC/PLL Specification
For Devices Operating at 1.2 V DC Core Voltage: Applicable to A3PE600L and A3PE3000L Only

Parameter	Min.	Typ.	Max.	Units
Clock Conditioning Circuitry Input Frequency f_{IN_CCC}	1.5		250	MHz
Clock Conditioning Circuitry Output Frequency f_{OUT_CCC}	0.75		250	MHz
Delay Increments in Programmable Delay Blocks ^{1, 2, 3}		360		ps
Number of Programmable Values in Each Programmable Delay Block			32	
Serial Clock (SCLK) for Dynamic PLL ⁴			100	MHz
Input cycle-to-cycle jitter (peak magnitude)			1	ns
Acquisition Time				
LockControl = 0			300	μs
LockControl = 1			6.0	ms
Tracking Jitter ⁵				
LockControl = 0			25	ns
LockControl = 1			1.5	ns
Output Duty Cycle	48.5		51.5	%
Delay Range in Block: Programmable Delay 1 ^{1, 2}	1.2		15.65	ns
Delay Range in Block: Programmable Delay 2 ^{1, 2}	0.025		15.65	ns
Delay Range in Block: Fixed Delay ^{1, 2}		3.5		ns
CCC Output Peak-to-Peak Period Jitter F_{CCC_OUT}	Max. Peak-to-Peak Period Jitter ^{6, 7}			
	SSO ≤ 2	SSO ≤ 4	SSO ≤ 8	SSO ≤ 16
0.75 MHz to 50 MHz	0.50%	0.60%	0.80%	1.60%
50 MHz to 160 MHz	2.50%	4.00%	6.00%	12.00%

Notes:

1. This delay is a function of voltage and temperature. See [Table 2-6 on page 2-6](#) for deratings.
2. $T_J = 25^{\circ}\text{C}$, $V_{CC} = 1.2\text{ V}$.
3. When the CCC/PLL core is generated by Microsemi core generator software, not all delay values of the specified delay increments are available. Refer to the [Libero online help](#) associated with the core for more information.
4. Maximum value obtained for a –1 speed grade device in worst-case military conditions. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.
5. Tracking jitter is defined as the variation in clock edge position of PLL outputs with reference to PLL input clock edge. Tracking jitter does not measure the variation in PLL output period, which is covered by period jitter parameter.
6. Measurements done with LVTTTL 3.3 V, 8 mA I/O drive strength and high slew rate. $V_{CC}/V_{CCPLL} = 1.14\text{V}$, VQ/PQ/TQ type of packages, 20 pF load.
7. Switching I/Os are placed outside of the PLL bank.

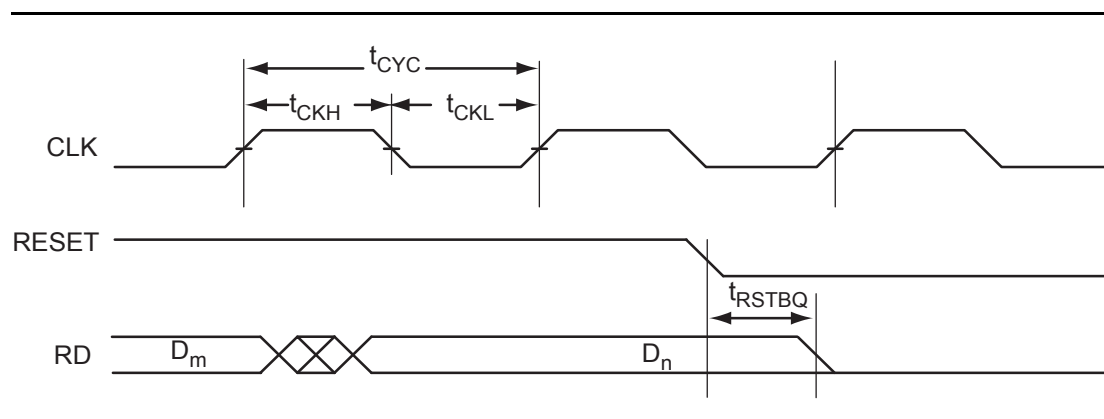


Figure 2-48 • RAM Reset

Timing Characteristics

Table 2-203 • RAM4K9
Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.14\text{ V}$ for A3PE600L and A3PE3000L

Parameter	Description	–1	Std.	Units
t_{AS}	Address setup time	0.35	0.41	ns
t_{AH}	Address hold time	0.00	0.00	ns
t_{ENS}	REN, WEN setup time	0.20	0.23	ns
t_{ENH}	REN, WEN hold time	0.13	0.16	ns
t_{BKS}	BLK setup time	0.32	0.38	ns
t_{BKH}	BLK hold time	0.03	0.03	ns
t_{DS}	Input data (DIN) setup time	0.25	0.30	ns
t_{DH}	Input data (DIN) hold time	0.00	0.00	ns
t_{CKQ1}	Clock High to new data valid on DOUT (output retained, WMODE = 0)	3.26	3.84	ns
	Clock High to new data valid on DOUT (flow-through, WMODE = 1)	2.47	2.91	ns
t_{CKQ2}	Clock High to new data valid on DOUT (pipelined)	1.24	1.46	ns
t_{C2CWWL}	Address collision clk-to-clk delay for reliable write after write on same address – applicable to closing edge	0.25	0.30	ns
t_{C2CRWH}	Address collision clk-to-clk delay for reliable read access after write on same address – applicable to opening edge	0.27	0.32	ns
t_{C2CRWH}	Address collision clk-to-clk delay for reliable write access after read on same address – applicable to opening edge	0.37	0.44	ns
t_{RSTBQ}	RESET Low to data out Low on DOUT (flow-through)	1.28	1.50	ns
	RESET Low to data out Low on DOUT (pipelined)	1.28	1.50	ns
$t_{REMRSTB}$	RESET removal	0.40	0.47	ns
$t_{RECRSTB}$	RESET recovery	2.08	2.44	ns
$t_{MPWRSTB}$	RESET minimum pulse width	0.66	0.76	ns
t_{CYC}	Clock cycle time	6.08	6.99	ns
F_{MAX}	Maximum frequency	164	143	MHz

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-204 • RAM4K9
Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$ for A3PE600L and A3PE3000L

Parameter	Description	–1	Std.	Units
t_{AS}	Address setup time	0.26	0.31	ns
t_{AH}	Address hold time	0.00	0.00	ns
t_{ENS}	REN, WEN setup time	0.15	0.18	ns
t_{ENH}	REN, WEN hold time	0.10	0.12	ns
t_{BKS}	BLK setup time	0.25	0.29	ns
t_{BKH}	BLK hold time	0.02	0.02	ns
t_{DS}	Input data (DIN) setup time	0.19	0.23	ns
t_{DH}	Input data (DIN) hold time	0.00	0.00	ns
t_{CKQ1}	Clock HIGH to new data valid on DOUT (output retained, WMODE = 0)	2.50	2.93	ns
	Clock HIGH to new data valid on DOUT (flow-through, WMODE = 1)	1.89	2.22	ns
t_{CKQ2}	Clock HIGH to new data valid on DOUT (pipelined)	0.95	1.11	ns
t_{C2CWWL}	Address collision clk-to-clk delay for reliable write after write on same address – applicable to closing edge	0.24	0.29	ns
t_{C2CRWH}	Address collision clk-to-clk delay for reliable read access after write on same address – applicable to opening edge	0.20	0.24	ns
t_{C2CRWH}	Address collision clk-to-clk delay for reliable write access after read on same address – applicable to opening edge	0.25	0.30	ns
t_{RSTBQ}	RESET Low to data out Low on DOUT (flow-through)	0.98	1.15	ns
	RESET Low to data out Low on DOUT (pipelined)	0.98	1.15	ns
$t_{REMRSTB}$	RESET removal	0.30	0.36	ns
$t_{RECRSTB}$	RESET recovery	1.59	1.87	ns
$t_{MPWRSTB}$	RESET minimum pulse width	0.59	0.67	ns
t_{CYC}	Clock cycle time	5.39	6.20	ns
F_{MAX}	Maximum frequency	185	161	MHz

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-216 • FIFO Worst Military-Case Conditions: $T_J = 125^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$ for A3P250 (4k×1)

Parameter	Description	–1	Std.	Units
t_{ENS}	REN, WEN Setup Time	5.85	6.87	ns
t_{ENH}	REN, WEN Hold Time	0.00	0.00	ns
t_{BKS}	BLK Setup Time	1.66	1.95	ns
t_{BKH}	BLK Hold Time	0.00	0.00	ns
t_{DS}	Input Data (WD) Setup Time	0.22	0.26	ns
t_{DH}	Input Data (WD) Hold Time	0.00	0.00	ns
t_{CKQ1}	Clock HIGH to New Data Valid on RD (flow-through)	2.84	3.33	ns
t_{CKQ2}	Clock HIGH to New Data Valid on RD (pipelined)	1.08	1.27	ns
t_{RCKEF}	RCLK HIGH to Empty Flag Valid	2.07	2.43	ns
t_{WCKFF}	WCLK HIGH to Full Flag Valid	1.96	2.31	ns
t_{CKAF}	Clock HIGH to Almost Empty/Full Flag Valid	7.45	8.76	ns
t_{RSTFG}	RESET LOW to Empty/Full Flag Valid	2.04	2.40	ns
t_{RSTAF}	RESET LOW to Almost Empty/Full Flag Valid	7.38	8.67	ns
t_{RSTBQ}	RESET LOW to Data Out LOW on RD (flow-through)	1.11	1.31	ns
	RESET LOW to Data Out LOW on RD (pipelined)	1.11	1.31	ns
t_{REMRSTB}	RESET Removal	0.34	0.40	ns
t_{RECRSTB}	RESET Recovery	1.81	2.12	ns
t_{MPWRSTB}	RESET Minimum Pulse Width	0.26	0.30	ns
t_{CYC}	Clock Cycle Time	3.89	4.57	ns
F_{MAX}	Maximum Frequency for FIFO	257	219	MHz

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

PQ208	
Pin Number	A3P1000 Function
1	GND
2	GAA2/IO225PDB3
3	IO225NDB3
4	GAB2/IO224PDB3
5	IO224NDB3
6	GAC2/IO223PDB3
7	IO223NDB3
8	IO222PDB3
9	IO222NDB3
10	IO220PDB3
11	IO220NDB3
12	IO218PDB3
13	IO218NDB3
14	IO216PDB3
15	IO216NDB3
16	VCC
17	GND
18	VCCIB3
19	IO212PDB3
20	IO212NDB3
21	GFC1/IO209PDB3
22	GFC0/IO209NDB3
23	GFB1/IO208PDB3
24	GFB0/IO208NDB3
25	VCOMPLF
26	GFA0/IO207NPB3
27	VCCPLF
28	GFA1/IO207PPB3
29	GND
30	GFA2/IO206PDB3
31	IO206NDB3
32	GFB2/IO205PDB3
33	IO205NDB3
34	GFC2/IO204PDB3
35	IO204NDB3
36	VCC

PQ208	
Pin Number	A3P1000 Function
37	IO199PDB3
38	IO199NDB3
39	IO197PSB3
40	VCCIB3
41	GND
42	IO191PDB3
43	IO191NDB3
44	GEC1/IO190PDB3
45	GEC0/IO190NDB3
46	GEB1/IO189PDB3
47	GEB0/IO189NDB3
48	GEA1/IO188PDB3
49	GEA0/IO188NDB3
50	VMV3
51	GNDQ
52	GND
53	VMV2
54	GEA2/IO187RSB2
55	GEB2/IO186RSB2
56	GEC2/IO185RSB2
57	IO184RSB2
58	IO183RSB2
59	IO182RSB2
60	IO181RSB2
61	IO180RSB2
62	VCCIB2
63	IO178RSB2
64	IO176RSB2
65	GND
66	IO174RSB2
67	IO172RSB2
68	IO170RSB2
69	IO168RSB2
70	IO166RSB2
71	VCC
72	VCCIB2

PQ208	
Pin Number	A3P1000 Function
73	IO162RSB2
74	IO160RSB2
75	IO158RSB2
76	IO156RSB2
77	IO154RSB2
78	IO152RSB2
79	IO150RSB2
80	IO148RSB2
81	GND
82	IO143RSB2
83	IO141RSB2
84	IO139RSB2
85	IO137RSB2
86	IO135RSB2
87	IO133RSB2
88	VCC
89	VCCIB2
90	IO128RSB2
91	IO126RSB2
92	IO124RSB2
93	IO122RSB2
94	IO120RSB2
95	IO118RSB2
96	GDC2/IO116RSB2
97	GND
98	GDB2/IO115RSB2
99	GDA2/IO114RSB2
100	GNDQ
101	TCK
102	TDI
103	TMS
104	VMV2
105	GND
106	VPUMP
107	GNDQ
108	TDO

FG484		FG484		FG484	
Pin Number	A3P1000 Function	Pin Number	A3P1000 Function	Pin Number	A3P1000 Function
K13	GND	M4	GFA2/IO206PDB3	N17	IO100NPB1
K14	VCC	M5	GFA1/IO207PDB3	N18	IO102NDB1
K15	VCCIB1	M6	VCCPLF	N19	IO102PDB1
K16	GCC1/IO91PPB1	M7	IO205NDB3	N20	NC
K17	IO90NPB1	M8	GFB2/IO205PDB3	N21	IO101NPB1
K18	IO88PDB1	M9	VCC	N22	IO103PDB1
K19	IO88NDB1	M10	GND	P1	NC
K20	IO94NPB1	M11	GND	P2	IO199PDB3
K21	IO98NDB1	M12	GND	P3	IO199NDB3
K22	IO98PDB1	M13	GND	P4	IO202NDB3
L1	NC	M14	VCC	P5	IO202PDB3
L2	IO200PDB3	M15	GCB2/IO95PPB1	P6	IO196PPB3
L3	IO210NPB3	M16	GCA1/IO93PPB1	P7	IO193PPB3
L4	GFB0/IO208NPB3	M17	GCC2/IO96PPB1	P8	VCCIB3
L5	GFA0/IO207NDB3	M18	IO100PPB1	P9	GND
L6	GFB1/IO208PPB3	M19	GCA2/IO94PPB1	P10	VCC
L7	VCOMPLF	M20	IO101PPB1	P11	VCC
L8	GFC0/IO209NPB3	M21	IO99PPB1	P12	VCC
L9	VCC	M22	NC	P13	VCC
L10	GND	N1	IO201NDB3	P14	GND
L11	GND	N2	IO201PDB3	P15	VCCIB1
L12	GND	N3	NC	P16	GDB0/IO112NPB1
L13	GND	N4	GFC2/IO204PDB3	P17	IO106NDB1
L14	VCC	N5	IO204NDB3	P18	IO106PDB1
L15	GCC0/IO91NPB1	N6	IO203NDB3	P19	IO107PDB1
L16	GCB1/IO92PPB1	N7	IO203PDB3	P20	NC
L17	GCA0/IO93NPB1	N8	VCCIB3	P21	IO104PDB1
L18	IO96NPB1	N9	VCC	P22	IO103NDB1
L19	GCB0/IO92NPB1	N10	GND	R1	NC
L20	IO97PDB1	N11	GND	R2	IO197PPB3
L21	IO97NDB1	N12	GND	R3	VCC
L22	IO99NPB1	N13	GND	R4	IO197NPB3
M1	NC	N14	VCC	R5	IO196NPB3
M2	IO200NDB3	N15	VCCIB1	R6	IO193NPB3
M3	IO206NDB3	N16	IO95NPB1	R7	GEC0/IO190NPB3

FG484		FG484		FG484	
Pin Number	A3PE3000L Function	Pin Number	A3PE3000L Function	Pin Number	A3PE3000L Function
H13	VCCIB1	K4	IO279NDB7V0	L17	GCA0/IO114NPB3V0
H14	VCCIB1	K5	IO283NDB7V1	L18	VCOMPLC
H15	VMV1	K6	IO281NDB7V0	L19	GCB0/IO113NPB2V3
H16	GBC2/IO84PDB2V0	K7	GFC1/IO275PPB7V0	L20	IO110PPB2V3
H17	IO83NDB2V0	K8	VCCIB7	L21	IO111NDB2V3
H18	IO100NDB2V2	K9	VCC	L22	IO111PDB2V3
H19	IO100PDB2V2	K10	GND	M1	GNDQ
H20	VCC	K11	GND	M2	IO255NPB6V2
H21	VMV2	K12	GND	M3	IO272NDB6V4
H22	IO105PDB2V2	K13	GND	M4	GFA2/IO272PDB6V4
J1	IO285NDB7V1	K14	VCC	M5	GFA1/IO273PDB6V4
J2	IO285PDB7V1	K15	VCCIB2	M6	VCCPLF
J3	VMV7	K16	GCC1/IO112PPB2V3	M7	IO271NDB6V4
J4	IO279PDB7V0	K17	IO108NDB2V3	M8	GFB2/IO271PDB6V4
J5	IO283PDB7V1	K18	IO108PDB2V3	M9	VCC
J6	IO281PDB7V0	K19	IO110NPB2V3	M10	GND
J7	IO287NDB7V1	K20	IO106NPB2V3	M11	GND
J8	VCCIB7	K21	IO109NDB2V3	M12	GND
J9	GND	K22	IO107NDB2V3	M13	GND
J10	VCC	L1	IO257PSB6V2	M14	VCC
J11	VCC	L2	IO276PDB7V0	M15	GCB2/IO116PPB3V0
J12	VCC	L3	IO276NDB7V0	M16	GCA1/IO114PPB3V0
J13	VCC	L4	GFB0/IO274NPB7V0	M17	GCC2/IO117PPB3V0
J14	GND	L5	GFA0/IO273NDB6V4	M18	VCCPLC
J15	VCCIB2	L6	GFB1/IO274PPB7V0	M19	GCA2/IO115PDB3V0
J16	IO84NDB2V0	L7	VCOMPLF	M20	IO115NDB3V0
J17	IO104NDB2V2	L8	GFC0/IO275NPB7V0	M21	IO126PDB3V1
J18	IO104PDB2V2	L9	VCC	M22	IO124PSB3V1
J19	IO106PPB2V3	L10	GND	N1	IO255PPB6V2
J20	GNDQ	L11	GND	N2	IO253NDB6V2
J21	IO109PDB2V3	L12	GND	N3	VMV6
J22	IO107PDB2V3	L13	GND	N4	GFC2/IO270PPB6V4
K1	IO277NDB7V0	L14	VCC	N5	IO261PPB6V3
K2	IO277PDB7V0	L15	GCC0/IO112NPB2V3	N6	IO263PDB6V3
K3	GNDQ	L16	GCB1/IO113PPB2V3	N7	IO263NDB6V3